	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10623767	YOSHINO ET AL.
	Examiner	Art Unit
	Cai, Wayne	2617

	ORIGINAL	AL	INTERNATION	INTERNATIONAL CLASSIFICATION	
CLASS		SUBCLASS	CLAIMED	NON-CLAIMED	
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<u> </u>	CROSS REFERENCE(S)	RENCE(S)			
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(Assistant Examiner)	(Date)	DUC	DUC M. NGUYEN SUPERVISORY PRIMARY EXAMINER	. 3	
		TECHNOIC	OGY CENTER 2600	O.G. Print Claim(s) O.G. P.	O.G. Print Figure
(Legal Instruments Examiner)	(Date)	(Primary Examiner)	(Date) //(7/0 /	-	₆

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